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Attorney Docket No. Q56532
PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Hideya TAKEO

Appln. No.: 09/489,846

Group Art Unit: 2721

Filed: January 24, 2000

Examiner: Not yet assigned

For: ABNORMAL PATTERN DETECTION PROCESSING METHOD AND SYSTEM

REQUEST FOR CORRECTED OFFICIAL FILING RECEIPT

Assistant Commissioner for Patents
Office of Initial Patent Examination
Customer Service Center
Washington, D.C. 20231

Sir:

We enclose a copy of the Official Filing Receipt for the above-identified application and request the following correction(s):

FOREIGN APPLICATIONS

JAPAN 14577/1999 01/22/1999

JAPAN 322707/1999 11/12/1999

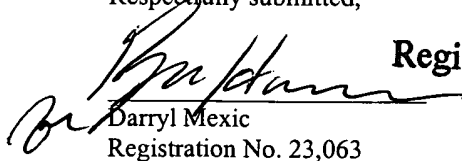
Verification for the requested correction(s) is indicated on the original Declaration and Power of Attorney filed January 24, 2000.

This error was caused by the PTO and therefore no fee is necessary.

Respectfully submitted,

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FILING RECEIPT

OC00000005020280

**UNITED STATES DEPARTMENT OF COMMERCE
Patent and Trademark Office**Address: ASSISTANT SECRETARY AND
COMMISSIONER OF PATENT AND TRADEMARKS
Washington, D.C. 20231

APPLICATION NUMBER	FILING DATE	GRP ART UNIT	FIL FEE REC'D	ATTY. DOCKET NO	DRAWINGS	TOT CLAIMS	IND CLAIMS
09/489,846 ✓	01/24/2000 ✓	2721	768 ✓	Q56532	9 ✓	✓	✓

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Receipt is acknowledged of this nonprovisional Patent Application. It will be considered in its order and you will be notified as to the results of the examination. Be sure to provide the U.S. APPLICATION NUMBER, FILING DATE, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this receipt. **If an error is noted on this Filing Receipt, please write to the Office of Initial Patent Examination's Customer Service Center. Please provide a copy of this Filing Receipt with the changes noted thereon. If you received a "Notice to File Missing Parts" for this application, please submit any corrections to this Filing Receipt with your reply to the Notice. When the PTO processes the reply to the Notice, the PTO will generate another Filing Receipt incorporating the requested corrections (if appropriate).**

Applicant(s)

Hideya Takeo, Kaisei-machi, JAPAN; ✓

Continuing Data as Claimed by Applicant

Foreign Applications JAPAN 14577/1999 01/22/1999
JAPAN 322707/1999 11/12/1999

If Required, Foreign Filing License Granted 03/30/2000

**

Title

Abnormal pattern detection processing method and system ✓

Preliminary Class

382

Data entry by : DADE, JOAN

Team : OIPE

Date: 03/30/2000

